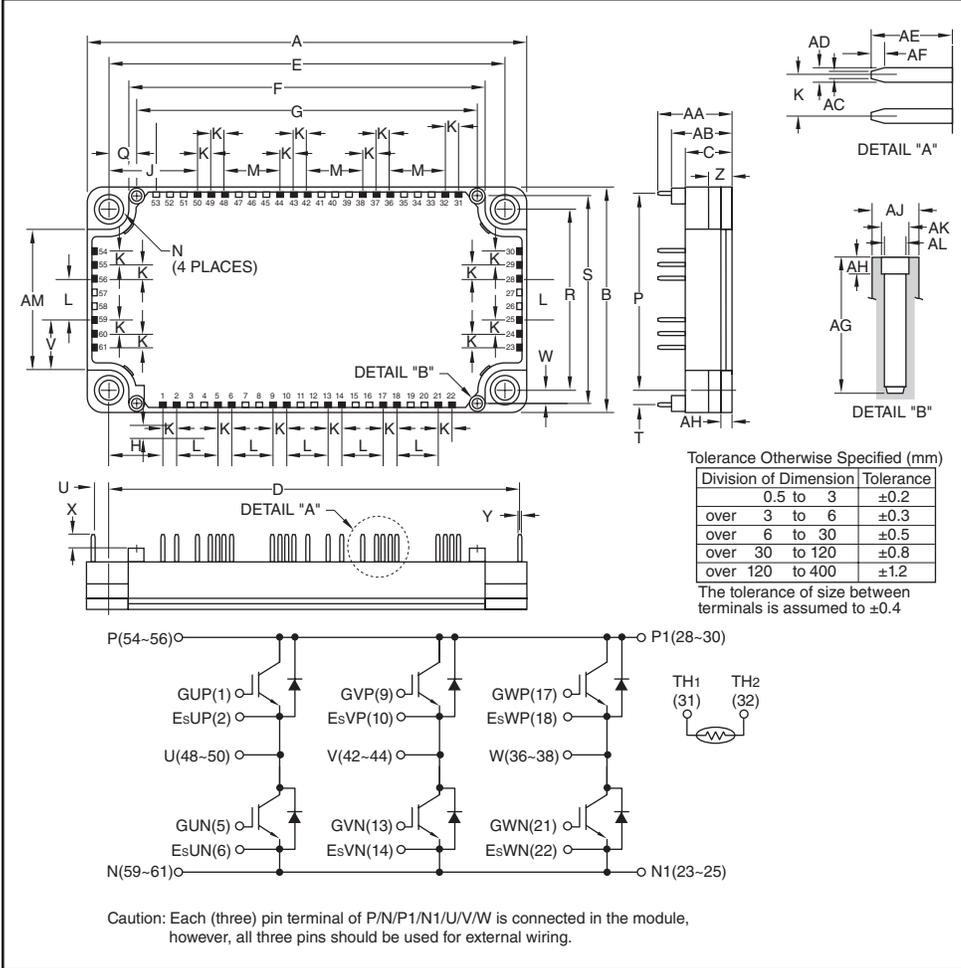


**Six IGBT
 NX-Series Module
 75 Amperes/1200 Volts**



Description:

Powerex IGBT Modules are designed for use in switching applications. Each module consists of six IGBT Transistors in a three phase bridge configuration with each transistor having a reverse-connected super-fast recovery free-wheel diode. All components and interconnects are isolated from the heat sinking baseplate, offering simplified system assembly and thermal management.

Features:

- Low Drive Power
- Low $V_{CE(sat)}$
- Discrete Super-Fast Recovery Free-Wheel Diode
- Isolated Baseplate for Easy Heat Sinking

Applications:

- AC Motor Control
- Motion/Servo Control
- Photovoltaic/Fuel Cell

Ordering Information:

Example: Select the complete module number you desire from the table below -i.e. CM75TX-24S is a 1200V (V_{CES}), 75 Ampere Six IGBT Power Module.

Outline Drawing and Circuit Diagram

Dimensions	Inches	Millimeters
A	4.79	121.7
B	2.44	62.0
C	0.51	13.0
D	4.49	114.05
E	4.33±0.02	110.0±0.5
F	3.9	99.0
G	3.72	94.5
H	0.59	15.0
J	0.96	24.52
K	0.15	3.81
L	0.45	11.43
M	0.6	15.24
N	0.22 Dia.	5.5 Dia.
P	2.13	54.2
Q	0.30	7.75
R	1.97±0.02	50.0±0.5
S	2.26	57.5
T	0.165	4.2

Dimensions	Inches	Millimeters
U	0.16	4.06
V	0.46	11.66
W	0.14	3.75
X	0.14	3.5
Y	0.03	0.8
Z	0.28	7.0
AA	0.81	20.5
AB	0.67	17.0
AC	0.03	0.65
AD	0.05	1.15
AE	0.29	7.4
AF	0.047	1.2
AG	0.49	12.5
AH	0.12	3.0
AJ	0.17 Dia.	4.3 Dia.
AK	0.102 Dia.	2.6 Dia.
AL	0.088 Dia.	2.25 Dia.
AM	1.53	39

Tolerance Otherwise Specified (mm)

Division of Dimension	Tolerance
0.5 to 3	±0.2
over 3 to 6	±0.3
over 6 to 30	±0.5
over 30 to 120	±0.8
over 120 to 400	±1.2

The tolerance of size between terminals is assumed to ±0.4

CM75TX-24S
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Absolute Maximum Ratings, $T_j = 25^\circ\text{C}$ unless otherwise specified

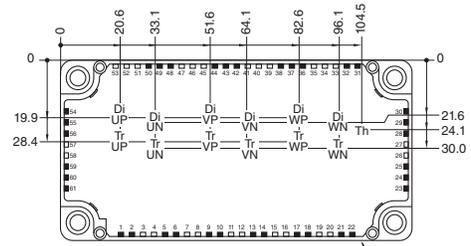
Inverter Part IGBT/FWDi

Characteristics	Symbol	Rating	Units
Collector-Emitter Voltage ($V_{GE} = 0V$)	V_{CES}	1200	Volts
Gate-Emitter Voltage ($V_{CE} = 0V$)	V_{GES}	± 20	Volts
Collector Current (DC, $T_C = 122^\circ\text{C}$)*2,*4	I_C	75	Amperes
Collector Current (Pulse)*3	I_{CRM}	150	Amperes
Total Power Dissipation ($T_C = 25^\circ\text{C}$)*2,*4	P_{tot}	600	Watts
Emitter Current ($T_C = 25^\circ\text{C}$)*2	I_E^{*1}	75	Amperes
Emitter Current (Pulse)*3	I_{ERM}^{*1}	150	Amperes

Module

Characteristics	Symbol	Rating	Units
Isolation Voltage (Terminals to Baseplate, RMS, $f = 60\text{Hz}$, AC 1 minute)	V_{ISO}	2500	Volts
Maximum Junction Temperature, Instantaneous Event (Overload)	$T_{j(max)}$	175	$^\circ\text{C}$
Maximum Case Temperature*2	$T_C(max)$	125	$^\circ\text{C}$
Operating Junction Temperature, Continuous Operation (Under Switching)	$T_{j(op)}$	-40 to +150	$^\circ\text{C}$
Storage Temperature	T_{stg}	-40 to +125	$^\circ\text{C}$

*1 Represent ratings and characteristics of the anti-parallel, emitter-to-collector free wheeling diode (FWDi).
 *2 Junction temperature (T_j) should not increase beyond maximum junction temperature ($T_{j(max)}$) rating.
 *3 Pulse width and repetition rate should be such that device junction temperature (T_j) does not exceed $T_{j(max)}$ rating.
 *4 Case temperature (T_C) and heatsink temperature (T_s) is measured on the surface (mounting side) of the baseplate and the heatsink side just under the chips. Refer to the figure to the right for chip location. The heatsink thermal resistance should be measured just under the chips.



Each mark points to the center position of each chip.
 Tr*P / Tr*N: IGBT Di*P / Di*N: FWDi Th: NTC Thermistor

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Electrical Characteristics, $T_j = 25^\circ\text{C}$ unless otherwise specified

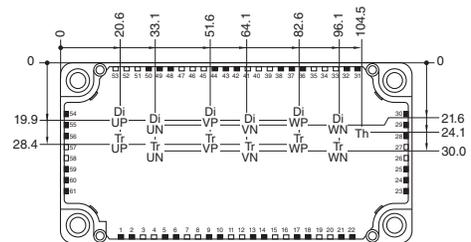
Inverter Part IGBT/FWDi

Characteristics	Symbol	Test Conditions	Min.	Typ.	Max.	Units
Collector-Emitter Cutoff Current	I_{CES}	$V_{CE} = V_{CES}, V_{GE} = 0V$	—	—	1	mA
Gate-Emitter Leakage Current	I_{GES}	$V_{GE} = V_{GES}, V_{CE} = 0V$	—	—	0.5	μA
Gate-Emitter Threshold Voltage	$V_{GE(th)}$	$I_C = 7.5\text{mA}, V_{CE} = 10V$	5.4	6	6.6	Volts
Collector-Emitter Saturation Voltage	$V_{CE(sat)}$ (Terminal)	$I_C = 75A, V_{GE} = 15V, T_j = 25^\circ\text{C}^{*5}$	—	1.80	2.25	Volts
		$I_C = 75A, V_{GE} = 15V, T_j = 125^\circ\text{C}^{*5}$	—	2.00	—	Volts
		$I_C = 75A, V_{GE} = 15V, T_j = 150^\circ\text{C}^{*5}$	—	2.05	—	Volts
Collector-Emitter Saturation Voltage	$V_{CE(sat)}$ (Chip)	$I_C = 75A, V_{GE} = 15V, T_j = 25^\circ\text{C}^{*5}$	—	1.70	2.15	Volts
		$I_C = 75A, V_{GE} = 15V, T_j = 125^\circ\text{C}^{*5}$	—	1.90	—	Volts
		$I_C = 75A, V_{GE} = 15V, T_j = 150^\circ\text{C}^{*5}$	—	1.95	—	Volts
Input Capacitance	C_{ies}		—	—	7.5	nF
Output Capacitance	C_{oes}	$V_{CE} = 10V, V_{GE} = 0V$	—	—	1.5	nF
Reverse Transfer Capacitance	C_{res}		—	—	0.13	nF
Gate Charge	Q_G	$V_{CC} = 600V, I_C = 75A, V_{GE} = 15V$	—	175	—	nC
Turn-on Delay Time	$t_{d(on)}$		—	—	300	ns
Rise Time	t_r	$V_{CC} = 600V, I_C = 75A, V_{GE} = \pm 15V,$	—	—	200	ns
Turn-off Delay Time	$t_{d(off)}$	$R_G = 8.2\Omega, \text{Inductive Load}$	—	—	600	ns
Fall Time	t_f		—	—	300	ns
Emitter-Collector Voltage	V_{EC}^{*1} (Terminal)	$I_E = 75A, V_{GE} = 0V, T_j = 25^\circ\text{C}^{*5}$	—	1.80	2.25	Volts
		$I_E = 75A, V_{GE} = 0V, T_j = 125^\circ\text{C}^{*5}$	—	1.80	—	Volts
		$I_E = 75A, V_{GE} = 0V, T_j = 150^\circ\text{C}^{*5}$	—	1.80	—	Volts
Emitter-Collector Voltage	V_{EC}^{*1} (Chip)	$I_E = 75A, V_{GE} = 0V, T_j = 25^\circ\text{C}^{*5}$	—	1.70	2.15	Volts
		$I_E = 75A, V_{GE} = 0V, T_j = 125^\circ\text{C}^{*5}$	—	1.70	—	Volts
		$I_E = 75A, V_{GE} = 0V, T_j = 150^\circ\text{C}^{*5}$	—	1.70	—	Volts
Reverse Recovery Time	t_{rr}^{*1}	$V_{CC} = 600V, I_E = 75A, V_{GE} = \pm 15V$	—	—	300	ns
Reverse Recovery Charge	Q_{rr}^{*1}	$R_G = 8.2\Omega, \text{Inductive Load}$	—	4.0	—	μC
Turn-on Switching Energy per Pulse	E_{on}	$V_{CC} = 600V, I_C = I_E = 75A,$	—	7.3	—	mJ
Turn-off Switching Energy per Pulse	E_{off}	$V_{GE} = \pm 15V, R_G = 8.2\Omega,$	—	8.0	—	mJ
Reverse Recovery Energy per Pulse	E_{rr}^{*1}	$T_j = 150^\circ\text{C}, \text{Inductive Load}$	—	6.9	—	mJ
Internal Lead Resistance	$R_{CC} + EE'$	Main Terminals-Chip, Per Switch, $T_C = 25^\circ\text{C}^{*4}$	—	—	2.4	m Ω
Internal Gate Resistance	r_g	Per Switch	—	0	—	Ω

*1 Represent ratings and characteristics of the anti-parallel, emitter-to-collector free wheeling diode (FWDi).

*4 Case temperature (T_C) and heatsink temperature (T_S) is measured on the surface (mounting side) of the baseplate and the heatsink side just under the chips. Refer to the figure to the right for chip location. The heatsink thermal resistance should be measured just under the chips.

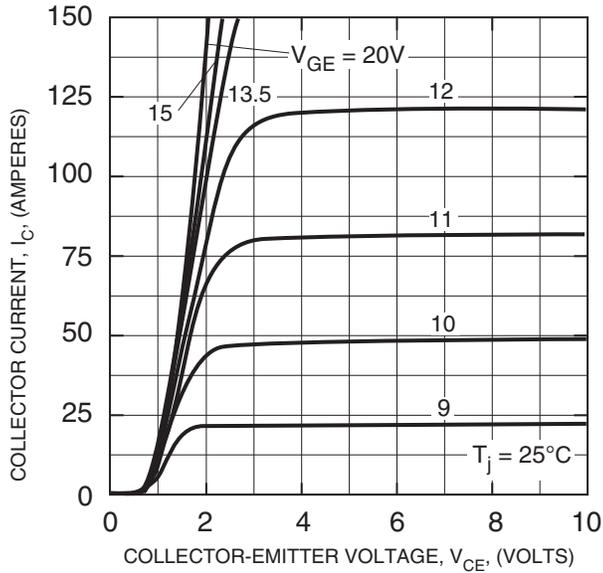
*5 Pulse width and repetition rate should be such as to cause negligible temperature rise.



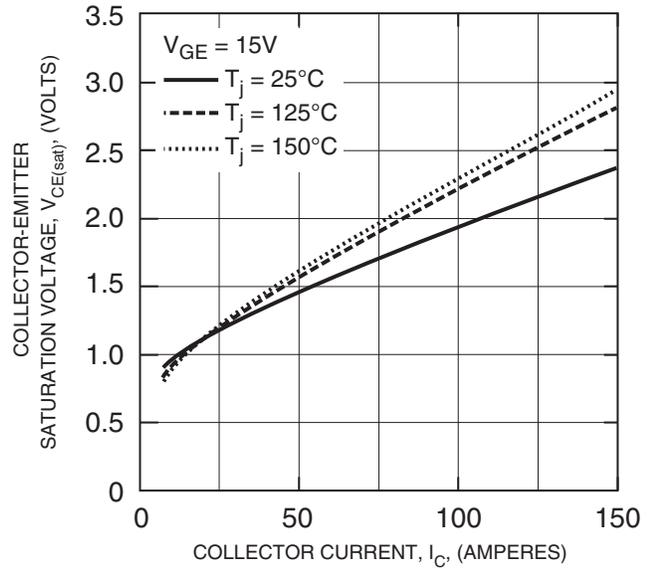
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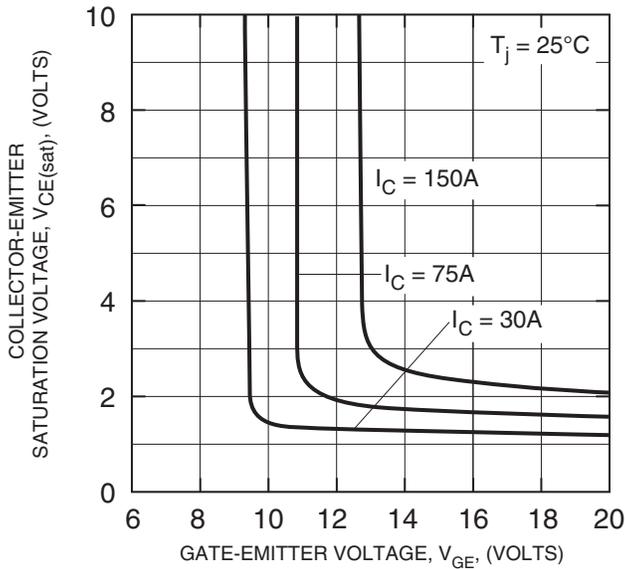
OUTPUT CHARACTERISTICS (TYPICAL)



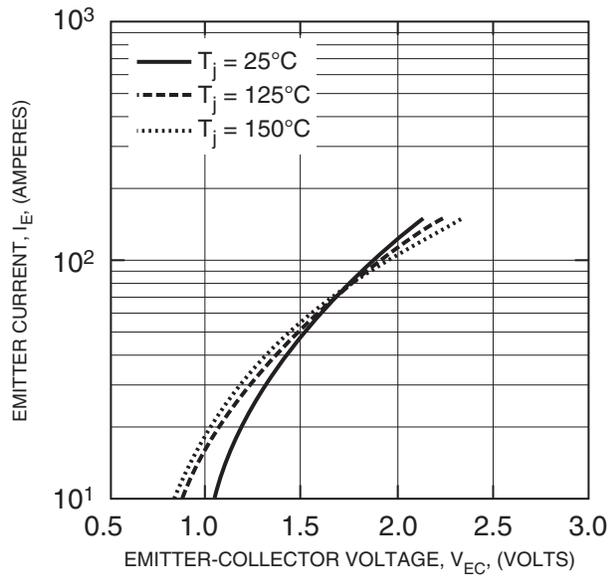
COLLECTOR-EMITTER SATURATION VOLTAGE CHARACTERISTICS (TYPICAL)



COLLECTOR-EMITTER SATURATION VOLTAGE CHARACTERISTICS (TYPICAL)

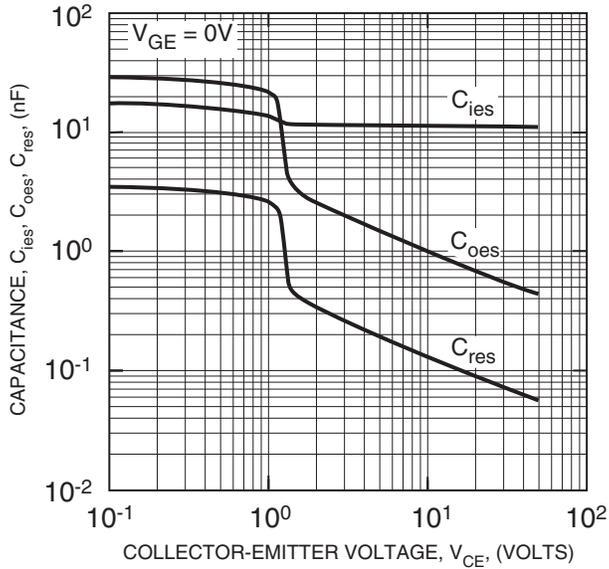


FREE-WHEEL DIODE FORWARD CHARACTERISTICS (TYPICAL)

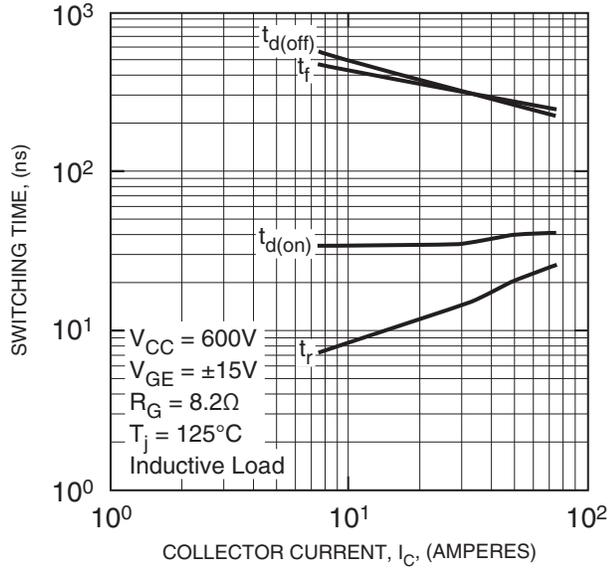


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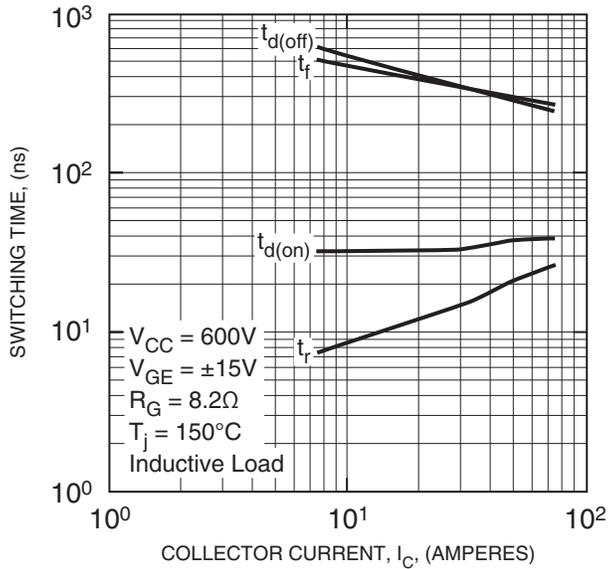
CAPACITANCE VS. V_{CE}
(TYPICAL)



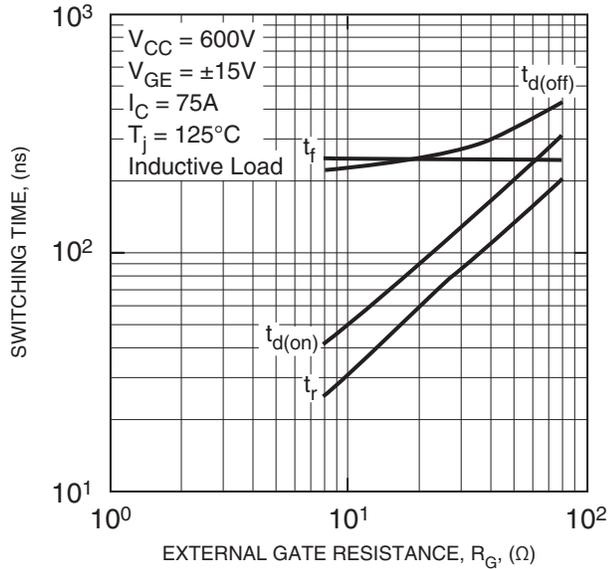
HALF-BRIDGE SWITCHING CHARACTERISTICS
(TYPICAL)



HALF-BRIDGE SWITCHING CHARACTERISTICS
(TYPICAL)

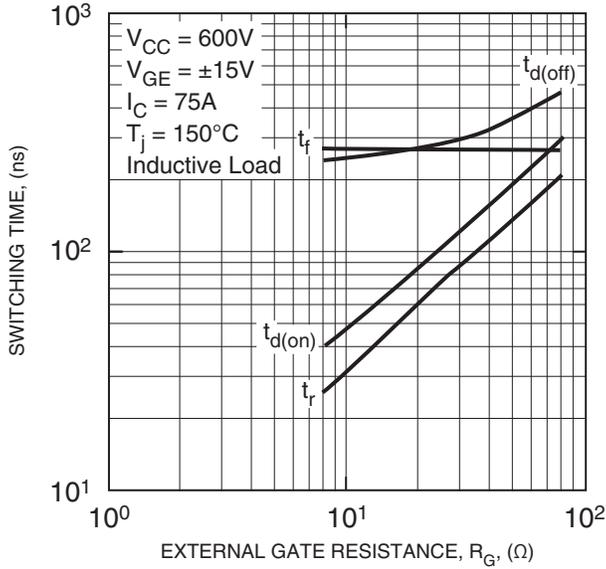


SWITCHING TIME VS. GATE RESISTANCE
(TYPICAL)

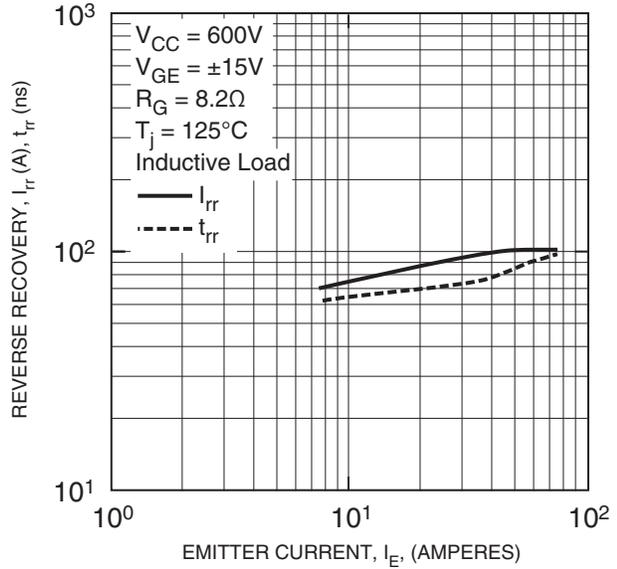


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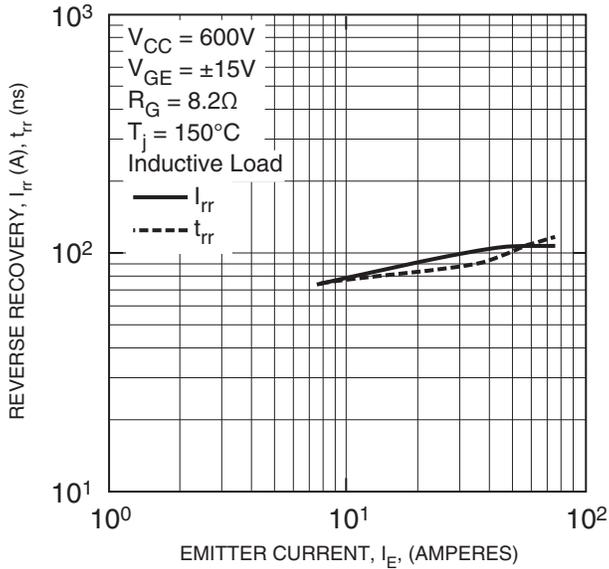
SWITCHING TIME VS. GATE RESISTANCE (TYPICAL)



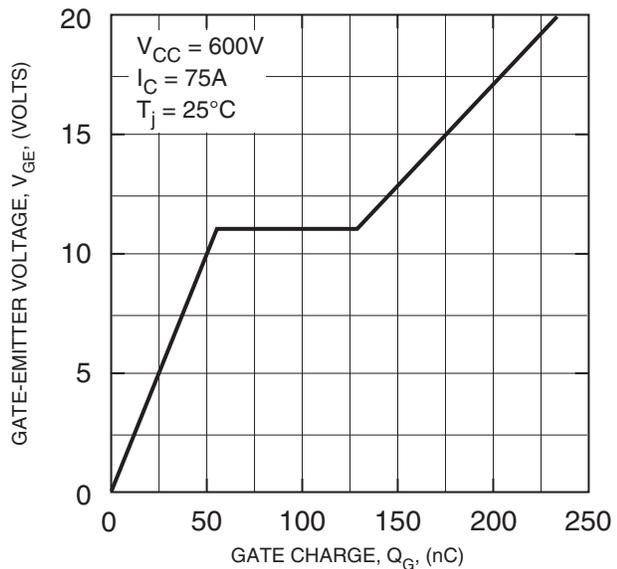
REVERSE RECOVERY CHARACTERISTICS (TYPICAL)



REVERSE RECOVERY CHARACTERISTICS (TYPICAL)

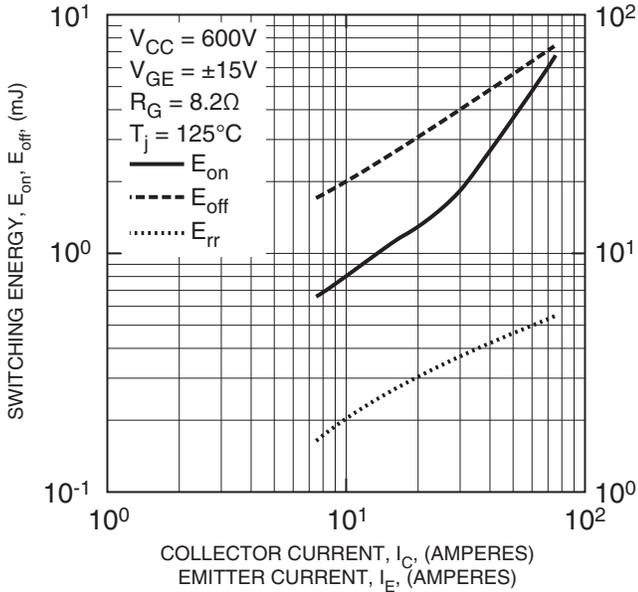


GATE CHARGE VS. V_GE

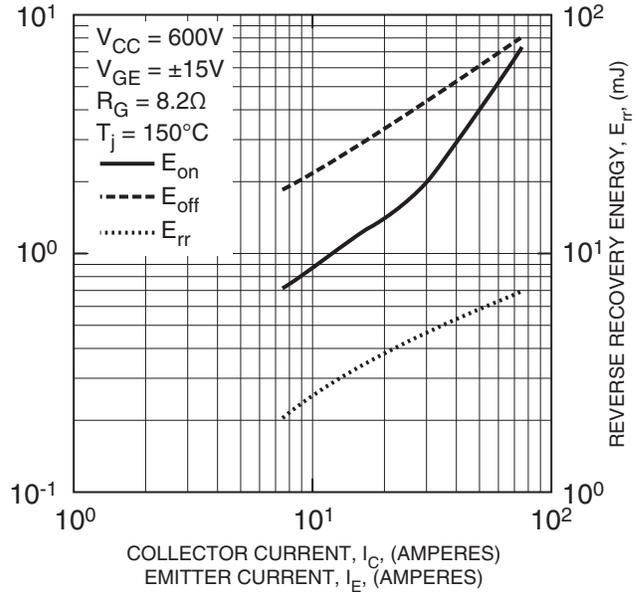


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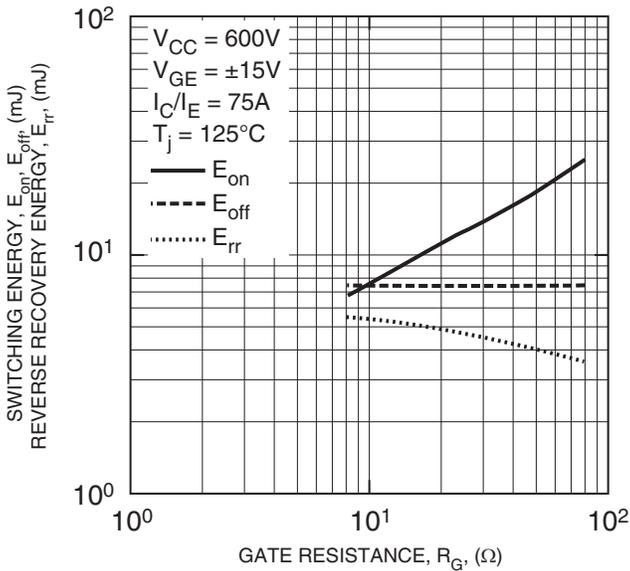
HALF-BRIDGE SWITCHING CHARACTERISTICS (TYPICAL)



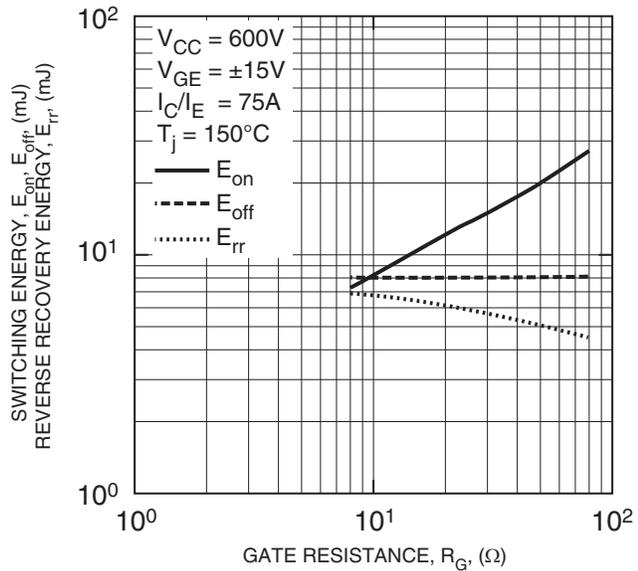
HALF-BRIDGE SWITCHING CHARACTERISTICS (TYPICAL)



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